

REMARKS

Each of the objections set forth in paragraphs 1 and 2 of the office action have been corrected.

With respect to the rejection set forth in paragraph 4, it is respectfully submitted that the cited article was not published in April 2002. In fact, the conference in question was not until October 2002. This is demonstrated by the attached Internet entry for a subsequent paper which cites the paper cited in the office action at paragraph 4. It clearly cites the conference and the conference as having occurred in October 7-10, 2002.

There is no basis for the assertion that the conference occurred in April.

Since the cited reference is authored by the inventors of the present application, no rejection under Section 102(a) would apply and the rejection under Section 102(b) must be withdrawn.

Therefore, reconsideration is requested.

Respectfully submitted,



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Coverage loss by using space compactors in presence of unknown values

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↑ ABSTRACT

The presence of unknown values in simulation is the greatest barrier to effective test response compaction. For space compactors, some responses may not be observable due to the masking effect caused by unknown values. This paper reports on experiments conducted to evaluate the impact on the test quality of various percentages of observable responses for both modeled and unmodeled faults.

↑ REFERENCES

Note: OCR errors may be found in this Reference List extracted from the full text article. ACM has opted to expose the complete List rather than only correct and linked references.

- 1 [Subhasish Mitra , Kee Sup Kim, X-Compact: An Efficient Response Compaction Technique for Test Cost Reduction, Proceedings of the 2002 IEEE International Test Conference, p.311, October 07-10, 2002](#)
- 2 [Chen Wang , Sudhakar M. Reddy , Irith Pomeranz , Janusz Rajski , Jerzy Tyszer, On](#)

Compacting Test Response Data Containing Unknown Values, Proceedings of the 2003 IEEE/ACM international conference on Computer-aided design, p.855, November 09-13, 2003 [doi>10.1109/ICCAD.2003.105]

- 3 J. Rajski, C. Wang, and S. M. Reddy, Convolutional Compaction Of Test Responses, IEEE International Test Conference, pp. 745--754, 2003.
- 4 Peter Wohl , Leendert Huisman, Analysis and Design of Optimal Combinational Compactors, Proceedings of the 21st IEEE VLSI Test Symposium, p.101, April 27-May 01, 2003
- 5 J. Savir, and S. Patil, Scan-based Transition Test, IEEE Trans. on Computer-Aided Design of Integrated Circuit and System, Vol.13(8), pp.1232--1241, 1993.

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